S/N 10/698,221

**PATENT** 

## IN THE UNITED STATES ATENT AND TRADEMARK OFFICE

Applicant:

MINEMOTO et al.

Examiner:

Unknown

Serial No.:

10/698,221

Group Art Unit:

2873

Filed:

October 31, 2003

Docket No.:

10873.1337US01

Title:

ULTRAVIOLET ACOUSTOOPTIC DEVICE AND OPTICAL IMAGING

APPARATUS USING THE SAME

**CERTIFICATE UNDER 37 CFR 1.8:** 

I hereby certify that this correspondence is being deposited with the United States Postal Service as first class mail, with sufficient postage, in an envelope addressed to: Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450 on March 17, 2004.

Name: Jennifer Holden

## INFORMATION DISCLOSURE STATEMENT (37 C.F.R. § 1.97(b))

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

Dear Sir:

With regard to the above-identified application, the items of information listed on the enclosed Form 1449 are brought to the attention of the Examiner. Enclosed for the Examiner's information is a copy of the European Search Report. At least some of the references were recently cited in a European Search Report mailed March 1, 2004.

This statement should be considered because it is submitted before the mailing date of a first Office Action on-the-merits. Accordingly, no fee is due for consideration of the items listed on the enclosed Form 1449.

In accordance with 37 C.F.R. §1.98(a)(2)(i), a copy of the U.S. patents and U.S. patent publications listed on the enclosed Form 1449 are not provided, as this application was filed after June 30, 2003. A copy of any foreign patent document or "Other Document" listed on the Form 1449 is enclosed, in accordance with 37 C.F.R. §1.98(a)(2).

A concise explanation of the relevance of each non-English language document or other information is as follows (37 C.F.R. §1.98(a)(3)):

EP 1 243 947 corresponds with U.S. 2003/007712.

No representation is made that a reference is "prior art" within the meaning of 35 U.S.C. §§ 102 and 103 and Applicants reserve the right, pursuant to 37 C.F.R. § 1.131 or otherwise, to establish that the reference(s) are not "prior art." Moreover, Applicants do not represent that a reference has been thoroughly reviewed or that any relevance of any portion of a reference is intended.

Consideration of the items listed is respectfully requested. Pursuant to the provisions of M.P.E.P. 609, it is requested that the Examiner return a copy of the attached Form 1449, marked as being considered and initialed by the Examiner, to the undersigned with the next official communication.

Please charge any additional fees or credit any overpayment to Deposit Account No. 13-2725.

Respectfully submitted,

MERCHANT & GOULD P.C.

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Dated: March 17, 2004

By:

Douglas P. Mueller

Reg. No. 30,300

DPM/jh

23552

FORM 1449*	INFORMATION DISCLOSURE STATISTICS	OIPE	Docket Number:	Application Number:						
	INFORMATION DISCLOSURE STATES	WENT	10873.1337US01	10/698,221						
	IN AN APPLICATION	MAR 2 2 2004 💆	Applicant: MINEMOTO et al.							
	(Use several sheets if necessary)	P. R. R.	Filing Date: October 31, 2003	Group Art Unit: 2873						
		& TRADEMAR								

			U.S. PATENT DOCUMEN	NTS			
EXAMINER INITIAL	DOCUMENT NO.	DATE	NAME	CLASS	SUBCLASS		G DATE OPRIATE
	2003/007712	01.2003	Ross-Messemer et al.				
	4,205,348	05.1980	DeBenedictis et al.				
	2001/030795	10.2001	Fujii et al.				•
	5,083,856	01.1992	Hatori et al.				
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		FO	REIGN PATENT DOCUM	IENTS			
	DOCUMENT NO.	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
****						YES	NO
	1 243 947	09.2002	ЕР			See IDS	
	ОТНЕ	DOCUMENT	'S (Including Author, Title, I	Date, Pertinent F	Pages, Etc.)	<u> </u>	
	"Investig Applied I	ation of intracav	rity third-harmonic generation and Optics), vol. B74, No. 2	n at 1.06 μm in 2, pp. 125-127 (2	YCa <sub>4</sub> O(BO <sub>3</sub> ) <sub>3</sub> cry	stals", by C. D	u et al.,
	"Points d pp. 1036-	"Points defects in Mg-doped lithium niobate" by K.L. Sweeney et al., Journal of Applied Physics, vol. 57, No. 4 pp. 1036-1044 (1985)					
	"Laser scanning for semiconductor mask pattern generation" by Paul C. Allen, Proceedings of The IEEE, v. No. 10 pp. 1653-1699 (2002)					EE, vol. 90	
				-		<del></del>	
	<del> </del>						

23552 Patent trademark office

EXAMINER	DATE CONSIDERED

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form for next communication to the Applicant.